

文章编号: 0253-2239(2005)07-980-4

高精度消色差相位延迟器的新设计

赵培涛 李国华 吴福全

(曲阜师范大学激光研究所, 曲阜 273165)

摘要: 消色差相位延迟器是在某一宽度光谱范围内使用的光相位延迟器件。从相位延迟的全反射相变理论出发,对斜入射消色差相位延迟原理进行阐述,参考菲涅耳棱镜的具体设计形式,对引起相位延迟变化的参量进行分析,通过选择合适的材料新设计出了特殊角度入射的高精度相位延迟器,其理论曲线显示,在 365~1150 nm 的光谱区域内延迟偏差小于 0.4° ,是常规相位延迟器在相同条件下的五分之一,是一种宽广谱范围内、负延迟偏差小、精度高的消色差相位延迟器。

关键词: 激光技术; 偏振与色散; 延迟器; 消色差; 高精度

中图分类号: O436.3 文献标识码: A

New Design of High Precision Achromatic Phase Retarder

Zhao Peitao Li Guohua Wu Fuquan

(Laser Institute of Qufu Normal University, Qufu 273165)

Abstract: Achromatic retarder is such a device that can be used in wide spectrum in optical phase retardation. Based on the total-reflection phase transformation theory of the phase retardation, the principle of achromatic phase retardation with oblique incident angle is expounded. And based on the detailed design of Fresnel rhomb, the parameters which induced the change of phase retardation are analyzed. The new achromatic retarder with the specific incident angle and high precision is designed by choosing suitable material in this paper. It is shown at the achromatic property curve within the range of 365 nm to 1150 nm theoretically that the retardation error is smaller than 0.4° , which is nearly one-fifth of the ordinary Fresnel rhomb phase retardation. So the new design retarder can be used in wide spectrum, at the same time it has the characteristic of small retardation error and high precision.

Key words: laser technique; polarization and dispersion; phase retarder; achromatic; high precision

1 引言

相位延迟器是激光调制中常用的光学元件,因其设计形式、类型及材料的不同而具有相当多的种类,但较为常用的还是由各向异性材料如云母、结晶石英等制成的波片及由各向同性材料制成的菲涅耳棱镜、蒙内菱形镜^[1]。在实际应用中常需要用到消色差相位延迟器。对云母或者石英波片常采用几片延迟量不同的波片以不同方位角复合的方式达到消色差的目的^[2~6];对于菱体形式的相位延迟器通常采用在内反射面蒸镀适当厚度的各种材料或者改进设计形式来达到消色差目的。如镀膜菲涅耳棱镜、蒙内菱形镜及消色差器 AD^[1]。菲涅耳棱镜及常规相位延迟器大都是让光线垂直入射端面,内反射角是确定不变的。由相位延迟公式可以看出相位延迟的大小只与材料

的折射率有关。若让光线斜入射到入射端面,则内反射角 θ 、入射角 i 、结构角 α 的关系可用一简单函数来表示^[11,12]。一方面,对于不同频率的光波,由于色散的影响引起折射率 n 的变化,使内反射角发生变化,因而相位延迟量发生改变;另一方面,折射率的改变将直接引起相位延迟量的改变。通过计算分析,对入射角、材料、结构角的适当选取,可以设计出特殊角度入射的高精度消色差相位延迟器。

2 斜入射相位延迟原理

光在界面处斜入射时,入射光波长 λ 改变时,折射角 t 将随折射率的改变而改变,所以全内反射角 θ 是折射率 n 的函数。当入射角 $i \neq 0$ 时,器件结构有

作者简介: 赵培涛(1980~),男,山东诸城人,曲阜师范大学硕士研究生,主要从事激光偏光理论、偏光技术及偏光器件的设计研究。E-mail: peitaozhao@163.com

收稿日期: 2004-06-28; 收到修改稿日期: 2004-10-13

如图 1 两种形式。两种结构形式的内反射角 θ 、入射角 i 、结构角 α 的关系可以用如下的函数表示:

$$(a) \text{ 结构形式: } \theta = \alpha - \arcsin(\sin i/n), \quad (1)$$

$$(b) \text{ 结构形式: } \theta = \alpha + \arcsin(\sin i/n), \quad (2)$$

斜入射时一次全内反射产生的相位延迟量可以表示为

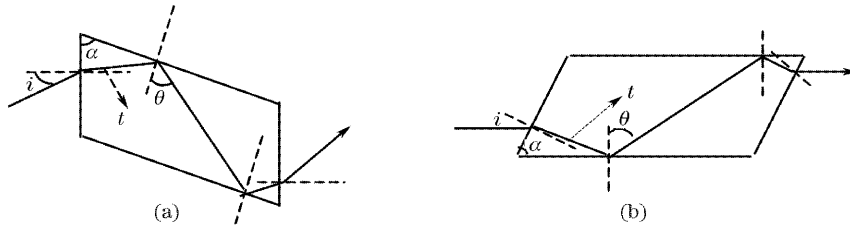


图 1 图 1 消色差延迟的两种形式

Fig. 1 Two different designs of achromatic retarder

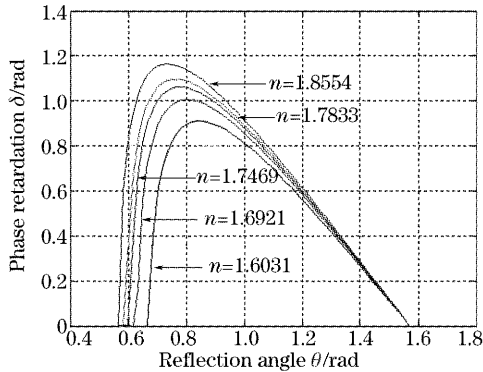


图 2 相位延迟 δ 随 n 和 θ 的变化

Fig. 2 The dependance of phase retardation δ on the total reflective angle θ for different refractive index material

对曲线进行分析可以看出:

1) 延迟量 δ 随折射率 n 的增大而增大, 即 $d\delta/dn > 0$ 。

2) 延迟量 δ 随全内反射角 θ 的变化分上升段和下降段两部分。上升段曲线延迟量随 θ 变化非常敏感, 变化率很大。下降段曲线延迟量随 θ 的变化比较平缓。

3) 对选用材料在波长 486~1150 nm 之间一般为正常色散, 折射率 n 随波长的增加而减小, 其全内反射角则随波长的增大受色散的影响增大。材料的这一物理特性为制作消色差延迟器提供了理论基础。当光线垂直入射到菲涅耳棱镜端面时, 全内反射角度为一定值, 因而当波长增加时, 相应折射率减小, 相应的延迟量减小, 因而不具有消色散性。可以通过选择特殊的入射角度及结构角, 使入射光波长变化时, 全内反射角也发生变化, 并且使这两种变化对相位延迟量的影响最小, 从而达到消色差目的。

$$\delta = 2 \arctan[\cos \theta (n^2 \sin^2 \theta - 1)^{1/2} / (n \sin^2 \theta)], \quad (3)$$

$$\delta = f_1(n, \theta), \quad \theta = f_2(n), \quad n = f_3(\lambda),$$

由相位延迟公式(3)知延迟量 δ 是折射率 n 和全内反射角 θ 的函数。利用 Matlab 作图工具作出延迟量 δ 随折射率 n 和全内反射角 θ 变化的关系图, 如图 2 所示。

3 特殊角入射消色差相位延迟器设计原理

对光波长发生变化时引起的相位延迟量一系列变化进行逐一分析。

1) 光波波长发生变化则对应的折射率要发生变化, 若选取正常色散的材料则波长变大时折射率要变小。

2) (a) 结构形式, 全内反射角 θ 随折射率 n 的增大而增大, 即 $d\theta/dn > 0$;

(b) 结构形式, 全内反射角 θ 随折射率 n 的增大而减小, 即 $d\theta/dn < 0$ 。

分析讨论消色差原理须从一次全内反射相位延迟公式出发。由相位延迟公式:

$$\tan\left(\frac{\delta}{2}\right) = \frac{\cos \sqrt{n^2 \sin^2 \theta - 1}}{n \sin^2 \theta}, \quad (4)$$

可以得到如下的关系式:

$$\Delta \delta = \left(\frac{\partial \delta}{\partial n}\right) \Delta n + \left(\frac{\partial \delta}{\partial \theta}\right) \Delta \theta, \quad \Delta \theta \approx \left(\frac{d\theta}{dn}\right) \Delta n, \quad (5)$$

由数学原理可以得到消色差相位延迟器的延迟误差表示式:

$$\frac{\Delta \delta}{\Delta n} = \left[\left(\frac{\partial \delta}{\partial n}\right) + \left(\frac{\partial \delta}{\partial \theta}\right) \left(\frac{d\theta}{dn}\right)\right], \quad (6)$$

只要(6)式值近似等于零, 使由于波长 λ 的变化引起相位延迟量 δ 的变化的两个方面相互抵消, 而达到消色散的目的。也就说明相位延迟器具有良好的消色散性。相位延迟量 δ 随全内反射角 θ 的变化关系:

$$\frac{\partial \delta}{\partial \theta} = 2 \frac{2n \sin \theta \cos^2 \theta - n^2 \sin^3 \theta + n \sin^3 \theta}{A}, \quad (7)$$

由于折射率 n 的变化引起全内反射角 θ 的变化可由(1)式, (2)式求导得到:

$$(a) \text{ 结构形式: } \frac{d\theta}{dn} = \frac{\sin i}{B},$$

$$(b) \text{ 结构形式: } \frac{d\theta}{dn} = -\frac{\sin i}{B},$$
(8)

(7)式、(8)式中

$$\begin{cases} A = (n^2 \sin^2 \theta - \cos^2 \theta) \sqrt{n^2 \sin^2 \theta - 1}, \\ B = n^2 \sqrt{1 - (\sin i/n)^2}, \end{cases}$$

相位延迟量 δ 随折射率 n 的变化关系可以由方程(4)得到:

$$\partial\delta/\partial n = 2(\sin^2\theta\cos\theta/A), \quad (9)$$

将各个式子代入到(6)式中并整理可以得到

$$\frac{\sin^2\theta\cos\theta}{A} = \frac{2n\sin\theta\cos^2\theta - n^3\sin^3\theta + n\sin^3\theta \left(\pm \frac{\sin i}{B}\right)}{A}. \quad (10)$$

当取(a)结构形式时(10)式取“+”;当取(b)结构

形式时(10)式取“-”。“+”“-”号的选取与计算结果无关,而取决于设计全内反射角在上升段曲线还是下降段曲线。并不是任意折射率的玻璃都能作为制作消色差相位延迟器的材料,满足方程(10)才可以。

在实际加工生产过程中,选用 LaK₂ 玻璃,在波长 $\lambda=587 \text{ nm}$ 时的折射率是 1.6921,将其代入内全反射相位延迟公式中可以解出 $\theta_1 = 60.58^\circ, \theta_2 = 38.81^\circ$ 。将 θ_1, θ_2 分别代入(10)式可解出对应的入射角的大小。其中 θ_2 代入后发现没有实解,故舍去。 θ_1 代入后求得对应的入射角 $i=44.95^\circ$ 。此时由于 $\theta_1=60.58^\circ$ 处于 $\delta-\theta$ 曲线的下降阶段,所以应该采用结构(a)的形式。其结构角 $\alpha=85.26^\circ$ 。

采用同样的分析方法,采用 LaK₃ 等型号的玻璃加工生产,其参量要求如下表 1 所示。

图 1 表 1 LaF₁₀, LaK₃ 的参量要求
Table 1 Parameters of LaK₃, LaF₁₀

Trademark of glass	Refractive index: n_d	Middle dispersion / 10^{-2}	Incidence angle / ($^\circ$)	Inner reflected angle / $^\circ$	Structure angle / ($^\circ$)	Structure shape
LaK ₂	1.69211	1.269	44.95	60.58	85.26	(a)
LaK ₃	1.74693	1.466	37.83	61.34	81.89	(a)
LaF ₁₀	1.78331	1.664	34.38	61.81	80.27	(a)
ZlaF ₃	1.85544	2.338	29.45	62.45	77.82	(a)

4 消色差理论曲线分析

从图 3、图 4 可以看出以下几点:

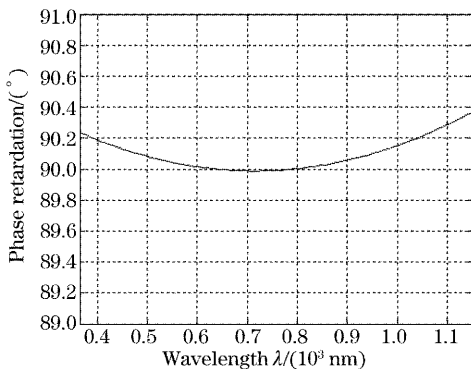


图 3 LaK₂ 延迟器的相位延迟理论值

Fig. 3 The theoretical phase retardation curve for achromatic LaK₂ retarder of new design

1) 新设计的相位延迟器的消色散性比常规菲涅耳棱镜的消色散性要好,从而具有非常高的延迟精度。常规菲涅耳棱镜的延迟偏差为 1.3° ,而新设计的相位延迟器在 $365.0 \sim 1150 \text{ nm}$ 非常宽的光谱范围内,延迟偏差不超过 0.4° 。

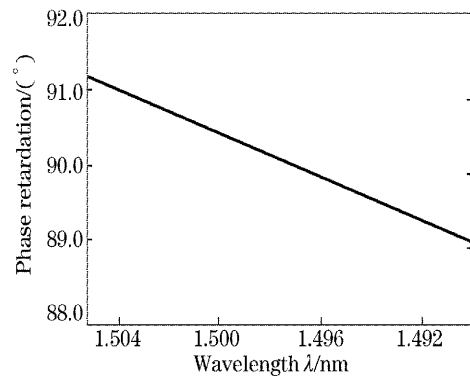


图 4 普通设计的延迟器的相位延迟与波长

Fig. 4 Variation of the retardation with refractive index for the ordinary design

2) 新设计的相位延迟器的相位延迟随波长的变化只发生相应微小变化,这是因为在考虑引起相位变化的两个因素的时候,在数学上采用了一级近似,见(5)式。使引起相位延迟变化的两方面的因素影响减小到最低限度,接近于零。但一很近似得出的结果已经相当好地满足消色差的要求。

5 有效通光孔径和长度的比值的关系探讨

如图 1 中(a)所示,光线从入射通光端面斜入射后经过两次全反射后由出射通光端面出射。在入射通光端面上不同位置入射的光线并不会全部经过两次全反射再经出射通光端面出射。有的光线可能只是经过一次全反射就直接入射到出射通光端面。这种光线的 S 分量和 P 分量的相位延迟差不是 90° , 不应该考虑在内。这就涉及到有效通光孔径的问题。同样,经过两次全反射后到达出射通光端面上的光线所形成的通光孔径只占出射通光端面的一部分。假定入射通光端面的长度为 h (考虑截面图), 菱体的长度为 L , 对于(a)结构形式的相位延迟器, 我们可以分析得到出射通光端面上的有效通光孔径和入射通光端面上的有效通光孔径相等, 记为 H , 其值可以通过计算得到:

$$H = L \cos \alpha + h \cos^2 \alpha - h \tan \theta \sin 2\alpha / 2 -$$

$$\tan(\alpha - \theta) \sin \alpha (L + h \cos \alpha - h \tan \theta \sin \alpha),$$

对 LaK₂ 材料制成的(a)型相位延迟器, 代入相关数值后可以得到有效通光孔径:

$$H = 0.3753L - 0.6322h.$$

6 结 论

我们在加工制作消色差相位延迟器的过程中总是采用(a)结构形式, 而且使内全反射角确定在 $\delta \sim \theta$ 曲线的下降段, 得出了与理论设计非常吻合的满意结果。基于对消色差延迟器件的这一新设计, 我们可以制作出不同材料高精度的消色差相位延迟器, 为激光偏光技术与偏光调制技术提供一种理想的高精度消色差延迟器。

参 考 文 献

- 1 Li Jingzhen. *Optical Handbook* [M]. Xi'an: Science and Technology Press of Shaanxi, 1986. 576~584
李影镇. 光学手册[M]. 西安: 陕西科学技术出版社, 1986. 576~584
- 2 Xu Wendong, Li Xishan. A new method for measuring phase delay of wave plate[J]. *Acta Optica Sinica*, 1994, **14**(10): 1096~1101 (in Chinese)
- 3 Li Hua, Song Lianke, Li Guohua. Orientation effect on phase retardation of compound binary zero-order waveplate[J]. *Acta Optica Sinica*, 2002, **22**(12): 1438~1441 (in Chinese)
- 4 Zhang Weiyan, Song Lianke, Li Guohua. Binary composite waveplate delay phase retardation effect[J]. *Optical Journal*, 2002, **22**(12): 1438~1441
- 5 Cheng Xiaotian, Li Yingzhu, Liu Cheng *et al.*. Method for measuring the retardation of a wave plate[J]. *Chin. J. Lasers*, 2003, **30**(7): 651~654 (in Chinese)
- 6 Wang Wei, Li Guohua, Wu Fuquan *et al.*. A new method of measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123 (in Chinese)
- 7 Wang Xia, Wu Fuquan, Shao Weidong. A Fresnel rhomb-type phase retarder insensitive to the incident angle [J]. *Laser Technology*, 2000, **24**(1): 27~29 (in Chinese)
- 8 Wang Xia, Wu Fuquan. Wang Hezhou. Discussion on retardation equation for achromatic phase retarder[J]. *Laser & Optoelectronics Progress*, 2001, (4): 14~17 (in Chinese)
- 9 Zhao Qiuling, Wu Fuquan. Optical phase retardation measurement by normalized polarization modulation [J]. *Acta Optica Sinica*, 2002, **22**(3): 360~362 (in Chinese)
- 10 Xu Guibao, Xu Xinguang, Yu Xiaoliang *et al.*. High resolution broadband optical isolator with Fresnel rhomb[J]. *Acta Optica Sinica*, 2003, **23**(8): 997~999 (in Chinese)
- 11 N. N. Nagib, M. S. El-Bahrawy. Phase retarders with variable angle of total internal reflection[J]. *Appl. Opt.*, 1994, **33**(7): 1218~1222
- 12 Wang Xia, Wu Fuquan. Theory of oblique-incidence achromatic phase retarder [J]. *J. Qufu Normal University (Natural Science)*, 2000, **26**(1): 57~59 (in Chinese)
- 13 Ma Wanli, Chen Liangrao, Zhou Shiming. The geometric design of an achromatic 1/4 wavelength retarder[J]. *Acta Photonica Sinica*, 2001, **30**(2): 236~239 (in Chinese)
- 14 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 15 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 16 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 17 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 18 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 19 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 20 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 21 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 22 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 23 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 24 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 25 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 26 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 27 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 28 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 29 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 30 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 31 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 32 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 33 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 34 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 35 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 36 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 37 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 38 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 39 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 40 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 41 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 42 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 43 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 44 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 45 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 46 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 47 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 48 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 49 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 50 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 51 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 52 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 53 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 54 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 55 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 56 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 57 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 58 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 59 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 60 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 61 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 62 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 63 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 64 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 65 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 66 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 67 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 68 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 69 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 70 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 71 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 72 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 73 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 74 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 75 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 76 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 77 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 78 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 79 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 80 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 81 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 82 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 83 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 84 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 85 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 86 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 87 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 88 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 89 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 90 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 91 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 92 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 93 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 94 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 95 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 96 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 97 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 98 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 99 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123
- 100 Wang Xia, Wu Fuquan. A new method for measuring wave plate phase delay and fast axis azimuth[J]. *Chin. J. Lasers*, 2003, **30**(2): 1121~1123